

Y. Watanabe S. Heun G. Salviati  
N. Yamamoto (Eds.)

# Nanoscale Spectroscopy and Its Applications to Semiconductor Research



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# Contents

## Introduction

<i>S. Heun, G. Salviati, Y. Watanabe, N. Yamamoto.....</i>	1
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## Part I Spectroscopy Using an Electron Microscope

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### Spectro-microscopy by TEM-SEM

<i>K. Yagi, Y. Tanishiro, H. Minoda.....</i>	11
--	----

### Determination of Nanosize Particle Distribution

#### by Low Frequency Raman Scattering:

#### Comparison to Electron Microscopy

<i>M. Ivanda, A.M. Tonejc, I. Djerdj, M. Gotić, S. Musić, G. Mariotto, M. Montagna.....</i>	24
---	----

### Development of Cathodoluminescence (CL)

#### for Semiconductor Research, Part I: TEM-CL Study

#### of Microstructures and Defects in Semiconductor Epilayers

<i>N. Yamamoto .....</i>	37
--------------------------	----

### Development of CL for Semiconductor Research, Part II:

#### Cathodoluminescence Study of Semiconductor Nanoparticles

#### and Nanostructures Using Low-Electron-Beam Energies

<i>T. Sekiguchi.....</i>	52
--------------------------	----

### Development of CL for Semiconductor Research, Part III:

#### Study of Degradation Mechanisms

#### in Compound Semiconductor-Based Devices by SEM-CL

<i>G. Salviati .....</i>	61
--------------------------	----

### Microcharacterization of Conformal GaAs on Si Layers

#### by Spatially Resolved Optical Techniques

<i>O. Martínez, M. Avella, A.M. Ardila, J. Jiménez, B. Gerad, E.G. Lafon ..</i>	74
---	----

### Strain Analysis in Submicron Electron Devices

#### by Convergent Beam Electron Diffraction

<i>A. Armigliato, R. Balboni, S. Frabboni, A. Benedetti, A.G. Cullis .....</i>	82
--	----

---

**Part II   X-ray Nanospectroscopy**

---

<b>Synchrotron Radiation X-ray Microscopy Based on Zone Plate Optics</b>	
<i>B. Kaulich, M. Kiskinova</i> . . . . .	93
<b>Long-Term Oxidation Behaviour of Lead Sulfide Surfaces</b>	
<i>K.C. Prince, S. Heun, L. Gregoratti, A. Barinov, M. Kiskinova</i> . . . . .	111
<b>Cross-Sectional Photoemission Spectromicroscopy of Semiconductor Heterostructures</b>	
<i>F. Barbo, M. Bertolo, A. Bianco, G. Cautero, R. Cimino, S. Fontana, A. Franciosi, T.K. Johal, S. La Rosa, D. Orani, M. Piccin, R.C. Purandare, S. Rubini, N. Svetchnikov</i> . . . . .	121
<b>Surface Imaging Using Electrons Excited by Metastable-Atom Impacts</b>	
<i>N. Ueno, H. Yasufuku, S. Kera, K.K. Okudaira, Y. Harada</i> . . . . .	131
<b>Application of Photoemission Electron Microscopy to Magnetic Domain Imaging</b>	
<i>T. Kinoshita</i> . . . . .	145
<b>Photoelectron Spectroscopy with a Photoemission Electron Microscope</b>	
<i>S. Heun, Y. Watanabe</i> . . . . .	157
<b>X-ray Photoemission and Low-Energy Electron Microscope</b>	
<i>R. Vašina, M. Mynář, V. Kolařík</i> . . . . .	172
<b>Application of Imaging-Type Photoelectron Spectromicroscopy to Solid-State Physics</b>	
<i>T. Kinoshita, Y. Haruyama</i> . . . . .	180

---

**Part III   Scanning Probe Spectroscopy**

---

<b>Scanning Near-Field Optical Spectroscopy of Quantum-Confining Semiconductor Nanostructures</b>	
<i>M. Colocci, V. Emiliani, P.G. Gucciardi, J. Kudrna, A. Vinattieri</i> . . . . .	199
<b>Novel Tuning Fork Sensor for Low-Temperature Near-Field Spectroscopy</b>	
<i>A. Crottini, J.L. Staehli, B. Deveaud, X.L. Wang, M. Ogura</i> . . . . .	210
<b>Manipulating, Reacting, and Constructing Single Molecules with a Scanning Tunneling Microscope Tip</b>	
<i>S.-W. Hla</i> . . . . .	222

<b>Electron-Beam-Induced Decomposition of SiO<sub>2</sub> Overlay on Si in STM Nanolithography</b>	
<i>H. Iwasaki, T. Ito, M. Gotoh, L. Nan, K. Sudoh</i>	231
<b>Direct Imaging of InGaAs Quantum Dot States by Scanning Tunneling Spectroscopy</b>	
<i>T.K. Johal, R. Rinaldi, A. Passaseo, R. Cingolani, A. Vasanelli, R. Ferreira, G. Bastard</i>	241
<b>Growth and Characterization of Ge Nanostructures on Si(111)</b>	
<i>F. Rosei, N. Motta, A. Sgarlata, A. Balzarotti</i>	252
<b>Imaging of Zero-Dimensional States in Semiconductor Nanostructures</b>	
<b>Using Scanning Tunneling Microscopy</b>	
<i>K. Kanisawa, M.J. Butcher, Y. Tokura, H. Yamaguchi, Y. Hirayama</i>	263
<b>Electronic-Excitation-Induced Enhancement in Metallicity on HOPG and Si Surfaces: In Situ STM/STS Studies</b>	
<i>J.P. Singh, D. Kanjilal</i>	269
<b>Electronic Properties of Polycrystalline and Amorphous WO<sub>3</sub> Investigated with Scanning Tunnelling Spectroscopy</b>	
<i>L. Ottaviano, E. Maccallini, S. Santucci</i>	278
<b>Probing of Electronic Transitions with Atomic-Scale Spatial Resolution</b>	
<b>in Semiconductor Quantum Well Structures</b>	
<i>S. Ushioda, T. Tsuruoka, Y. Ohizumi, R. Tanimoto</i>	287
<b>Scanning Tunneling Microscope-Induced Light Emission from Nanoscale Structures</b>	
<i>M. Sakurai</i>	294
<b>Index</b>	305